

Search Notes**Application/Control No.**

10/073,756

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	537	10/26/2005	BQN
370	466	10/26/2005	BQN
370	395.51	10/26/2005	BQN
359	125	10/26/2005	BQN
359	124	10/28/2005	BQN
359	110	10/28/2005	BQN
370	347	10/28/2005	BQN
370	242-250	10/28/2005	BQN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	10/26/2005	BQN
Consulted with Wellington Chin	10/27/2005	BQN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner